

**Notice of References Cited**Application/Control No.  
**09/763,092**Applicant(s)/Patent Under Reexam  
**Miyajima**Examiner  
**Daniel G. DePumpo**Art Unit  
**3611**

Page 1 of 1

**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
A	5,128,196	7/1992	Luetkens, Jr. et al.	428	213
B	5,375,677	12/1994	Yamagiwa et al.	180	219
C	6,135,542	10/2000	Emmelmann et al.	296	205
D	5,040,803	8/1991	Cieslik et al.	277	12
E	4,978,562	12/1990	Wycech	296	146.6
F	5,678,826	10/1997	Miller	277	316
G	5,102,188	4/1992	Yamane	296	901
H	5,806,915	9/1998	Takabatake	296	91
I	4,751,249	6/1988	Wycech	521	54
J					
K					
L					
M					

**FOREIGN PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Country</b>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
N						
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**NON-PATENT DOCUMENTS**

	<b>Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages</b>
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